Search Notes				

Application/Control No.	Applicant(s)/Patent (Reexamination	under
10/649,717	TAMURA, NORIKO	<u></u>
Examiner	Art Unit	•
Nicholas T. La	2617	_

SEAR	Date	Examiner
Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
John Peng	8/10/2006	NL	
Charles Appiah	8/10/2006	NL	
3.11. F. 1. P.			